

UV-Thermal Combined Stress Acceleration Test

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Background and Purpose

Over 30 years long life PV module is expected

∆Pm as the index of degradation is very small.
⇒To evaluate 30 years life time, it needs few months even if combined stress acceleration test is adopted.

In the STD's test, long term thermal stress tests are performed without light irradiated stress.

Purpose is to figure out the acceleration rate of the UV-thermal combined stress test and to find out what type of failure appears.



Experimental apparatus

Specifications			
item	spec		
temperature control (w/ o irradiation)	- 40 ~ +90 °C		
temperature control (w/ irradiation under 3UV)	+50 ~ +90 °C		
humidity control (w/ o irradiation over room temp.)	(max) RH 85± 5%		
maximum irradiance	3 UV		
temporal instability of irradiance	under 10%		
non-uniformity of irradiance in the test plane	under 15%		
maximum sample size	1218H x 445W		
sample capacity	3 panels		

Acceleration Test: UV-Thermal Combined Stress





Testing recipe

(1) continuous irradiation and high temperature [HT.Irr] Test : HT.Irr continuous irradiation: 3UV or 1UV module temperature: 90°C or 65°C Degradation of window materials output terminal: open

(2) TC w/ irradiation @ high temperature [T Test : TC.Irr irradiation @ high temperature: 3UV module temperature: 75°C 1hr, -20 °C 1hr (2hr / 1cycle), repeat cycles output terminal: open



Test modules

2 models (companies) were selected as test modules. Outdoor exposure test has started since 2007 in Miyakojima, Okinawa by JET.

Module A				Мо	dule-B
		$\left \begin{array}{c} \\ \\ \\ \\ \end{array} \right $	Model		xxxx
			Nominal maximum output	t	153W
			Nominal open cirtuit volt	age	25.61V
			Nominal short circuit cur	rent	8.21A
Model	xxxx		Nominal maximum output	t voltage	20.30V
Nominal maximum output	45W		Nominal maximum output	t current	7.54A
Nominal open cirtuit voltage	6.0V		Dimension		1165 x 990 x 46mm
Nominal short circuit current	7.50A		Weight		14.5ka
Nominal maximum output voltage	7.4V				
Nominal maximum output current	8.28A				
Dimension	W972 x L 345 x H8				
Weight	3.7 ka				

Module A (multi-crystalline 156mm x 156mm 12 cells, $972H \times 345W$) Module B (multi-crystalline 156mm x 156mm 14 cells, $1180H \times 355W$)



Isolation of IV curve



Evaluate Δ Isc of each cell as degradation index

Degradation factors, estimation of acceleration ratios Test : HT.Irr



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Calculation of acceleration ratio

Basis (Tokyo) : $T_0 = 60^{\circ}C$, $A_0 = 3.6 \text{kWh} \cdot \text{m}^{-2}/\text{day}$ Test condition : $T_t = 90^{\circ}C$, $A_t = 3UV \cdot 24 \text{hr}$ irradiation

 $\begin{array}{l} \rightarrow \text{calculate the acceleration ratio} & \left\{ \begin{matrix} \alpha_1^{\text{r}} \\ \alpha \end{matrix} \right\} \\ \alpha = \left(\begin{matrix} -\frac{A_t}{A_0} \end{matrix} \right) & exp \left\{ \begin{matrix} \alpha_2^{\text{r}} \\ \frac{A_t}{k} \end{matrix} \right\} \\ \left\{ \begin{matrix} \alpha_1^{\text{r}} \\ \frac{A_t}{k} \end{matrix} \right\} \\ \left\{ \begin{matrix} \alpha_1^{\text{r$



Delamination from TC w/ Irrad



Control test: TC w/o Irrad, delamination occurred

⇒ Delamination originates from thermal cycle



Additional test modules

Test : TC.Irr





Swells in back sheet

test recipe	cumulative test hours	line No.
3UV, 90degC	230	1
3UV, TC	280	2
75degC ~ - 20degC	330	3
3UV TC	380	4
75degC ~ - 40degC	480	5
	580	6



Relative position - cell No. and J-Box:indicates J-BOX viewed from the back sheet side of module.

Pictures represent swells: Similar swells appeared in other cells in No. 5, 6, 7, 9, 10, 11, 12, 13, 14, 16.



Cell No. 4





Improvement?





Conclusion

(1) As for the factor for irradiation, the difference between module A and B was small, but that for temperature, it was large.

(2) The acceleration ratio obtained from UV-thermal combined stress test was about 100. Degradation of window materials is not so large.

(3)From TC.Irr test, it was shown that cell design such as finger electrode or J-Box affects on failures.



Thank you for kind attention!

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